

P-Channel Enhancement Mode MOSFET

Features

Pin Description

-30V/-8A ,

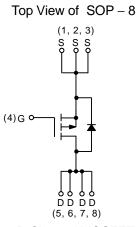
$$R_{DS(ON)}$$
=16m Ω (typ.) @ V_{GS} =-10V
 $R_{DS(ON)}$ =24m Ω (typ.) @ V_{GS} =-4.5V

- Super High Dense Cell Design
- · Reliable and Rugged
- · SOP-8 Package
- · Lead Free Available (RoHS Compliant)

Applications

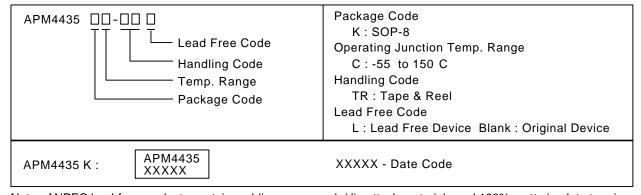
Power Management in Notebook Computer,
 Portable Equipment and Battery Powered
 Systems





P-Channel MOSFET

Ordering and Marking Information



Note: ANPEC lead-free products contain molding compounds/die attach materials and 100% matte in plate termination finish; which are fully compliant with RoHS and compatible with both SnPb and lead-free soldiering operations. ANPEC lead-free products meet or exceed the lead-free requirements of IPC/JEDEC J STD-020C for MSL classification at lead-free peak reflow temperature.

ANPEC reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.



Absolute Maximum Ratings (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Rating	Unit		
V_{DSS}	Drain-Source Voltage	-30	V		
V_{GSS}	Gate-Source Voltage		±25	V	
l _D *	Continuous Drain Current		-8	А	
I _{DM} *	Pulsed Drain Current		-30	ζ	
l _S *	Diode Continuous Forward Current	-3	А		
T_J	Maximum Junction Temperature	Maximum Junction Temperature			
T _{STG}	Storage Temperature Range	-55 to 150	°C		
D *	T _A =25°C		2	W	
P _D *	Maximum Power Dissipation $T_A=100^{\circ}C$		0.8	V V	
$R_{\theta JA}^*$	Thermal Resistance-Junction to Ambient		62.5	°C/W	

Note:

Electrical Characteristics $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

Cumbal	Parameter	Test Condition	А	PM4435	ίΚ	Unit	
Symbol	Farameter Test Condition		Min.	Тур.	Max.	J.I.R	
Static Ch	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =-250μA	-30			V	
1	Zoro Coto Voltago Drain Current	V _{DS} =-24V, V _{GS} =0V			-1	^	
I _{DSS}	Zero Gate Voltage Drain Current	T _A =25°C	;		-30	μΑ	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=-250\mu A$	-1	-1.5	-2	V	
I _{GSS}	Gate Leakage Current	$V_{GS}=\pm25V, V_{DS}=0V$			±100	nA	
р а	Drain-Source On-state Resistance	V _{GS} =-10V, I _{DS} =-8A		16	20	mΩ	
R _{DS(ON)} a	Dialii-Source Oil-state Resistance	V _{GS} =-4.5V, I _{DS} =-5A		24	30		
V _{SD} ^a	Diode Forward Voltage	I _{SD} =-3A, V _{GS} =0V		-0.8	-1.3	V	
Dynamic	Characteristics ^b						
R _G	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz		10		Ω	
C _{iss}	Input Capacitance	$V_{GS}=0V$,		3200			
C _{oss}	Output Capacitance	V _{DS} =-25V,		560		pF	
C _{rss}	Reverse Transfer Capacitance	Frequency=1.0MHz		250			
t _{d(ON)}	Turn-on Delay Time			16	30		
T _r	Turn-on Rise Time	V_{DD} =-15V, R_L =15 Ω ,		17	32	no	
t _{d(OFF)}	Turn-off Delay Time	I_{DS} =-1A, V_{GEN} =-10V, R_G =6 Ω ,		75	136	ns	
T _f	Turn-off Fall Time]		31	57		

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^{*}Surface Mounted on $1in^2$ pad area, $t \le 10sec$.



Electrical Characteristics (Cont.) $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

Symbol	Parameter	Parameter Test Condition		APM4435K		
Syllibol	raiailletei	rest Condition	Min.	Тур.	Max.	Unit
Gate Char	ge Characteristics ^b					
Q_g	Total Gate Charge			48	60	
Q_gs	Gate-Source Charge	V _{DS} =-15V, V _{GS} =-10V, I _{DS} =-8A		10		nC
Q_gd	Gate-Drain Charge	טיין – 5טיין		9		

Notes:

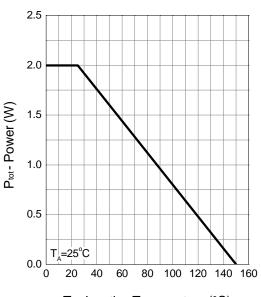
a : Pulse test ; pulse width≤300µs, duty cycle≤2%.

b: Guaranteed by design, not subject to production testing.



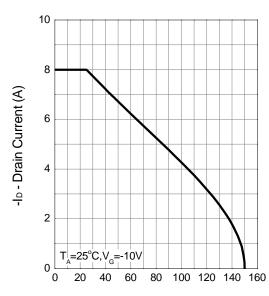
Typical Characteristics

Power Dissipation



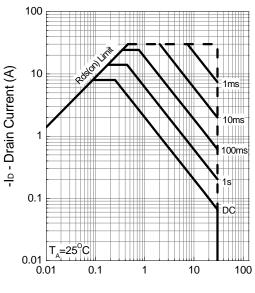
T_j- Junction Temperature (°C)

Drain Current



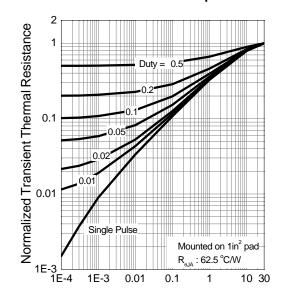
T_j - Junction Temperature (°C)

Safe Operation Area



-V_{DS} - Drain - Source Voltage (V)

Thermal Transient Impedance

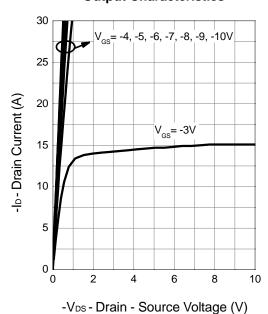


Square Wave Pulse Duration (sec)

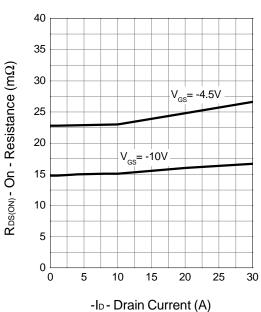


Typical Characteristics (Cont.)

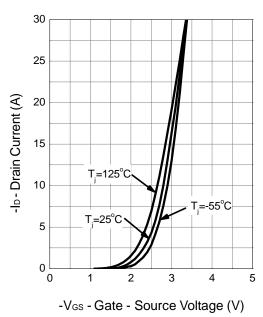
Output Characteristics



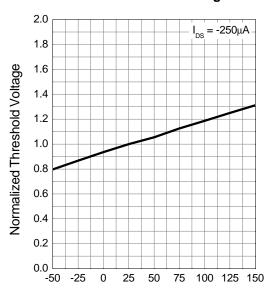
Drain-Source On Resistance



Transfer Characteristics



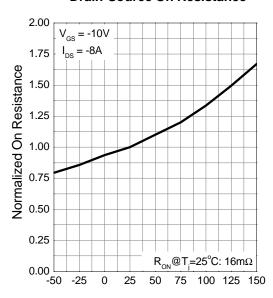
Gate Threshold Voltage





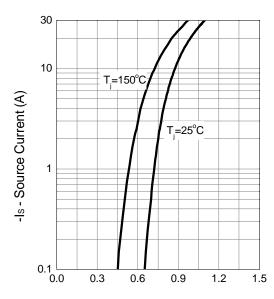
Typical Characteristics (Cont.)

Drain-Source On Resistance



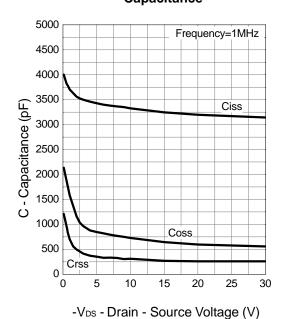
T_j - Junction Temperature (°C)

Source-Drain Diode Forward

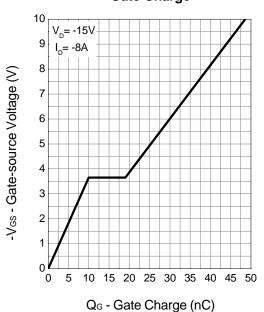


-Vsp - Source - Drain Voltage (V)

Capacitance



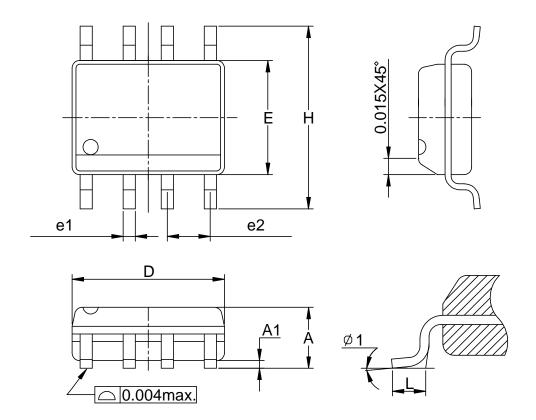
Gate Charge





Packaging Information

SOP-8 pin (Reference JEDEC Registration MS-012)



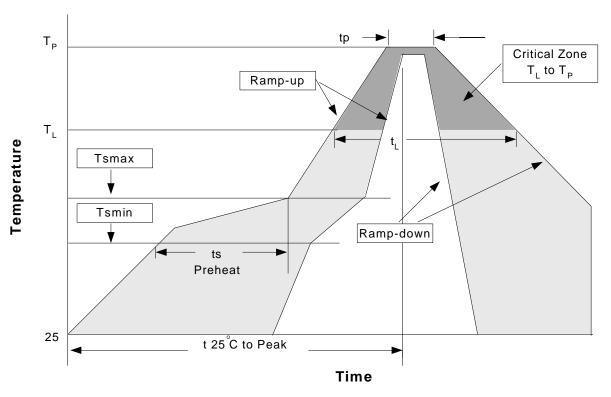
Dim	Millim	neters	Incl	hes
Dim	Min.	Max.	Min.	Max.
Α	1.35	1.75	0.053	0.069
A1	0.10	0.25	0.004	0.010
D	4.80	5.00	0.189	0.197
E	3.80	4.00	0.150	0.157
Н	5.80	6.20	0.228	0.244
L	0.40	1.27	0.016	0.050
e1	0.33	0.51	0.013	0.020
e2	1.27BSC		0.50	BSC
φ 1	8	0	8	0



Physical Specifications

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb), 100%Sn
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.

Reflow Condition (IR/Convection or VPR Reflow)



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate $(T_L \text{ to } T_P)$	3°C/second max.	3°C/second max.
Preheat - Temperature Min (Tsmin) - Temperature Max (Tsmax) - Time (min to max) (ts)	100°C 150°C 60-120 seconds	150°C 200°C 60-180 seconds
Time maintained above: - Temperature (T _L) - Time (t _L)	183°C 60-150 seconds	217°C 60-150 seconds
Peak/Classificatioon Temperature (Tp)	See table 1	See table 2
Time within 5°C of actual Peak Temperature (tp)	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.	6°C/second max.
Time 25°C to Peak Temperature	6 minutes max.	8 minutes max.

Notes: All temperatures refer to topside of the package .Measured on the body surface.



Classification Reflow Profiles(Cont.)

Table 1. SnPb Entectic Process - Package Peak Reflow Temperatures

Package Thickness	Volume mm³ <350	Volume mm ³ 350
<2.5 mm	240 +0/-5°C	225 +0/-5°C
≥2.5 mm	225 +0/-5°C	225 +0/-5°C

Table 2. Pb-free Process – Package Classification Reflow Temperatures

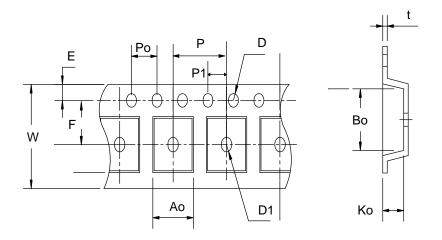
Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm³ >2000
<1.6 mm	260 +0°C*	260 +0°C*	260 +0°C*
1.6 mm – 2.5 mm	260 +0°C*	250 +0°C*	245 +0°C*
≥2.5 mm	250 +0°C*	245 +0°C*	245 +0°C*

^{*}Tolerance: The device manufacturer/supplier **shall** assure process compatibility up to and including the stated classification temperature (this means Peak reflow temperature +0°C. For example 260°C+0°C) at the rated MSL level.

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C,5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
TST	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

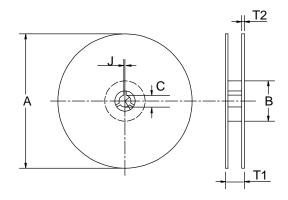
Carrier Tape & Reel Dimensions



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Carrier Tape & Reel Dimensions(Cont.)



Application	Α	В	С	J	T1	T2	W	Р	Е
	330±1	62 ± 1.5	12.75 +	2 + 0.5	12.4 +0.2	2± 0.2	12 + 0.3	8± 0.1	1.75± 0.1
			0.1 5				- 0.1		
SOP-8	F	D	D1	Po	P1	Ao	Во	Ko	t
SOP-8	F 5.5 ± 0.1	D 1.55±0.1	D1 1.55+ 0.25			_		_	t 0.3±0.013

(mm)

Cover Tape Dimensions

Application	Carrier Width	Cover Tape Width	Devices Per Reel
SOP-8	12	9.3	2500

Customer Service

Anpec Electronics Corp.

Head Office:

No.6, Dusing 1st Road, SBIP,

Hsin-Chu, Taiwan, R.O.C.

Tel: 886-3-5642000 Fax: 886-3-5642050

Taipei Branch:

7F, No. 137, Lane 235, Pac Chiao Rd.,

Hsin Tien City, Taipei Hsien, Taiwan, R. O. C.

Tel: 886-2-89191368 Fax: 886-2-89191369

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